

Battery Pack Test Report UN38.3

Customer: Lenovo

Pack Model: SB10K97573

Nominal voltage: 15.2V

Nominal capacity:32Wh/2.11Ah

Configuration: 4S1P

ASM P/N:SB10K97573

FRU P/N:01AV416

Celxpert P/N: 921300088

Cell Type: Coslight CA583864HV 2110mAh

Jan. 22, 2018

Approved by 实验室

Prepared by A



Figure photo of the pack







For Use With ThinkPad 锂离子电池组 NOM 15.2V == 32Wh ,2.11Ah Rechargeable Li-ion Battery 额定容量:2060mAh 充电限制电压: 17.40V CAUTION: Replace with same Use of another battery may pre PLEASE REFER TO USER M ORDINANCES AND/OR REG Cell made in China/Pack processed in China EU contact:Lenovo,Einsteinova 2 注意:用错误型号电池更换会

PS:此報告僅針對送檢樣品有效

The test report is valid for the tested samples only.

制造商:加百裕工业股份有限公司

制造地/製造地:中国/中國



1. UN38.3 Test Report										
Test Period	2016/02/23~2	2016/03/12	Test Spec.	ST/SG/AC.10/11/Rev.5 Amend.2						
Parts Name	Battery Pack Application		NB	Quantity	Pack 16PCS/Cell 25pcs					

1.1 Test Summary

Item	Test Item	Test Result	Details
T1	Altitude simulation test (UN38.3-1)	Pass	Page 9
T2	Thermal test (UN38.3-2)	Pass	Page 10
Т3	Vibration test (UN38.3-3)	Pass	Page 11
T4	Shock test (UN38.3-4)	Pass	Page 12
T5	Short Circuit test (UN38.3-5)	Pass	Page 13
T6	Crush Test (UN38.3-6)	Pass	Page 13
T7	Overcharge test (UN38.3-7)	Pass	Page 14
T8	Forced discharge test (UN38.3-8)	Pass	Page 15

The battery pack passes UN38.3 test.



1.2 Test sample list

No.	Pack S/N	Test item	No.	Cell Num.	Test item
1	Sample No:1/16	38.3.1~5	1	Coslight CA583864HV 2110mAh	38.3.6
2	Sample No:2/16	38.3.1~5	2	Coslight CA583864HV 2110mAh	38.3.6
3	Sample No:3/16	38.3.1~5	3	Coslight CA583864HV 2110mAh	38.3.6
4	Sample No:4/16	38.3.1~5	4	Coslight CA583864HV 2110mAh	38.3.6
5	Sample No:5/16	38.3.1~5	5	Coslight CA583864HV 2110mAh	38.3.6
6	Sample No:6/16	38.3.1~5	6	Coslight CA583864HV 2110mAh	38.3.8
7	Sample No:7/16	38.3.1~5	7	Coslight CA583864HV 2110mAh	38.3.8
8	Sample No:8/16	38.3.1~5	8	Coslight CA583864HV 2110mAh	38.3.8
9	Sample No:9/16	38.3.7	9	Coslight CA583864HV 2110mAh	38.3.8
10	Sample No:10/16	38.3.7	10	Coslight CA583864HV 2110mAh	38.3.8
11	Sample No:11/16	38.3.7	11	Coslight CA583864HV 2110mAh	38.3.8
12	Sample No:12/16	38.3.7	12	Coslight CA583864HV 2110mAh	38.3.8
13	Sample No:13/16	38.3.7	13	Coslight CA583864HV 2110mAh	38.3.8
14	Sample No:14/16	38.3.7	14	Coslight CA583864HV 2110mAh	38.3.8
15	Sample No:15/16	38.3.7	15	Coslight CA583864HV 2110mAh	38.3.8
16	Sample No:16/16	38.3.7	16	Coslight CA583864HV 2110mAh	38.3.8
			17	Coslight CA583864HV 2110mAh	38.3.8
			18	Coslight CA583864HV 2110mAh	38.3.8
			19	Coslight CA583864HV 2110mAh	38.3.8
			20	Coslight CA583864HV 2110mAh	38.3.8
			21	Coslight CA583864HV 2110mAh	38.3.8
			22	Coslight CA583864HV 2110mAh	38.3.8
			23	Coslight CA583864HV 2110mAh	38.3.8
			24	Coslight CA583864HV 2110mAh	38.3.8
			25	Coslight CA583864HV 2110mAh	38.3.8



1.3 Test result

1.3 Test	resuit											
Item	Test Item		Te	st specification	on	Judo	ge criteria	Sample(s)				
Т1	Altitude Simulation (UN38.3-1)	1-2.E c r 1-2.E c r 1-3.\	patteries are patteries when the control of the con	are standard control of the st		4 packs are charged (Pa 4 packs 50 cending in full states (Pack	ck#1~4) ycled y charged					
Test Per	iod		t: 2016/02		End:2016/02	2/23						
Test Equ	ipment				F Q090, 真空		6					
Major Pr		女 位		-, t , /C	, <u> </u>	-//\/IE \\ \\	-					
Warning		-										
		Tha	hattonur	oacks pass	the test							
Recomm	nendation	me	battery p	backs pass	s trie test.							
			Altitude Simulation Test on Charged Packs									
		No	Be	efore	Afte	er	voltage residue	mass loss	other event			
	No	No.	OCV	Weight	OCV	Weight	Volt	Weight	Outer event			
		1	(V) 15.362	(g) 156.17	(V) 15.360	(g) 156.16	(%) 99.99%	0.00%	0			
		2	15.359	156.34	15.358	156.33	99.99%	0.00%	0			
		3	15.367	156.28	15.366	156.27	99.99%	0.00%	0			
		4	15.355	156.22	15.352	156.21	99.98%	0.00%	0			
		5	15.338	156.15	15.336	156.14	99.99%	0.01%	0			
		6	15.341	156.29	15.338	156.28	99.98%	0.01%	0			
		7	15.326	156.31	15.325	156.30	99.99%	0.01%	0			
		8	15.334	156.24	15.330	156.23	99.97%	0.01%	0			
					sembly ; R-Rupture Disassembly , No I							
Rav	v Data											



Item	Test Item		Τe	est specification	n		J	udge criteria	Samp	ole(s)
T2	Thermal test (UN38.3-2)	followed by storage for 6 hours at -40±2°C. no leak The maximum time interval between test temperature extremes is 30 minutes. Battery 2-2.Repeat 2-1 for 10 times. Then store the packs at ambient for 24 hours. All packs weight are measured. The charged battery voltage are measured and recorded.						ss loss (<0.1%), kage, no venting, assembly, no e and no fire. y voltage drop <	4 packs are stacharged (Pack 4 packs 50 cyc fully charged s (Pack#5~8)	#1~4) cled ending in
Test Per	iod	Star	t: 2016/02	2/24	End:2016	/03/	01			
Test Equ	ipment			3, 電子天平				 ∳ Q336		
Major Pr		- I		-, -0 + / €		* 102	-1 T W	<u> </u>		
		_								
Warning			naaka n	noo the tee	.+					
Recomn	nendation	me	packs pa	ass the tes	il.					
					Therma	l Test	on Cha	arged Packs		
			Ве	efore	Af	ter		voltage residue	mass loss	
	No.	OCV	Weight	OCV	We	eight	Volt	Weight	other event	
			(V)	(g)	(V)		g)	(%)	(%)	
		1	15.360	156.16	15.291		5.14	99.55%	0.02%	0
		3	15.358 15.366	156.33 156.27	15.282 15.291		5.29 5.25	99.51%	0.02%	0
		4	15.352	156.21	15.278		5.19	99.52%	0.01%	0
		5	15.336	156.14	15.265		5.11	99.54%	0.02%	0
		6	15.338	156.28	15.263	156	5.25	99.51%	0.02%	0
		7	15.325	156.30	15.257	156	5.28	99.56%	0.02%	0
		8	15.330	156.23	15.255	156	5.20	99.51%	0.02%	0
Rav	v Data		_	/enting; D-Disass, No Venting, No I				Fire		



Item	Test Item	Test specification Judge criteria							Sa	ample(s)	
Т3	Vibration test (UN38.3-3)	3-1. Packs are firmly secured to the platform of the vibration machine without distorting the packs in such a manner as to faithfully transmit the vibration. The vibration shall be a sinusoidal waveform with a logarithmic sweep between 7 and 200 Hz and back to 7 Hz traversed in 15 minutes. This cycle shall be repeated 12 times for a total of 3 hours for each of 3 mutually perpendicular to the terminal face. 3-2. The logarithmic frequency sweep is as follows: 7-18 Hz → 1gn 18-50 Hz → 0.8mm amplitude 50-200 Hz → 8gn 3-3. All packs weight are measured. The charged packs voltage are measured and recorded.								4 packs charged	are standard (Pack#1~4) 50 cycled n fully states
Test Per	iod	Sta	rt: 2016/0	3/04 E	nd:2016/	03/05		l			
Test Equ	ipment	數位	:電表 Q15	i3, 電子天	平 Q090,	振動測試	.機 Q	156			
Major Pr	oblem	-									
, Warning		-									
	nendation	The	packs p	ass the te	st.						
						tion Test on	Charge	ed Packs			
		No. Before		Af	ter	volt	age residue		ss loss	other event	
		140.	OCV (V)	Weight (g)	OCV (V)	Weight (g)		Volt (%)		eight (%)	Outer event
		1	15.291	156.14	15.284	156.11		99.95%		.02%	0
		2	15.282	156.29	15.275	156.27		99.95%		.02%	0
		3	15.291 15.278	156.25 156.19	15.283 15.270	156.23 156.17		99.95% 99.95%		.02%	0
		5	15.265	156.11	15.257	156.09		99.95%		.02%	0
		6	15.263	156.25	15.257	156.22		99.96%	0.	.02%	0
		7	15.257	156.28	15.248	156.25		99.94%		.02%	0
		8	15.255	156.20	15.248	156.18		99.95%	0.	.02%	0
				Venting ; D-Disas , No Venting , No			No Fire				
Rav	w Data		Ŭ.		·						



	Toot Itom			Test specific	Judge criteria	Som	nple(s)		
Item	Shock test (UN38.3-4)	4-2. 4-2. 1 1 1 4-3. /	Packs shall by means of all mounting Packs shall of peak accept 6 millisect to 3 shocks three shocks mutually per the pack for All batteries charged cell recorded.	4 packs are standard charged (Pack#1~4) 4 packs 50 cycled ending in fully charged states (Pack#5~8)					
Test Per	iod	Star	t: 2016/03	3/07	End:2016/0	3/07		1	
Test Equ	uipment				平 Q090, 衝		∵機 Ω154		
-		安 人/12	- 电水 Q10	O, 电 1 八 ·	, QUUU , 倒	于州四	VADA CETOT		
Major Pi									
Warning	Point	-							
Recomn	nendation	The	packs p	ass the te	st.				
		Shock Test on Charged Packs Before After voltage residue						mass loss	
		No.	OCV	Weight	OCV	Wei	_	Weight	other event
			(V)	(g)	(V)	(9		(%)	_
		2	15.284	156.11 156.27	15.278 15.270	156. 156.		0.00%	0
		3	15.283	156.23	15.278	156.		0.00%	0
		4	15.270	156.17	15.264	156.		0.00%	0
		5	15.257	156.09	15.253	156.	08 99.97%	0.00%	0
		6	15.257	156.22	15.250	156.		0.00%	0
		7	15.248	156.25	15.242	156.		0.00%	0
		8	15.248	156.18	15.243	156.	17 99.97%	0.00%	0
Ra	w Data		O-No Leakage	, No Venting , No	Disassembly , No	Rupture ,	No Fire		



Test Item		Test specification		Jud	ge criteria		Sample(s)			
Short Circuit Test (UN38.3-5)	ext 5-2.Who sho wird 5-4. The or t	erior packs temperature are en packs exterior reach 55± orted by connecting terminal e of resistance less than 100 e short was continued for mother cell temperature return to	disasser explosic smoke. exterior	mbly, no n, no fire, no Packs peak	charge 4 pack	ss are standard ed (Pack#1~4) ss 50 cycled ending charged states #5~8)				
iod	Start: 2016/03/10 End:2016/03/12									
ipment	數位電	表 Q153, 資料收集器	Q075, 烘箱 C	Q171						
nendation		·								
				/ent						
Raw Data										
	6		0							
	7	55.69	0							
	8	55.47	0	0						
	Note: I	D-Disassembly : R-Ruptu								
				ire						
Test Item					Judge criter	ia	Sample(s)			
Crush test/ Impact test (UN38.3-6)	(A 9.1 k 61±2.5d 6-2.Cel (The ce	I's diameter > 20mm, Executing mass is to be dropped from onto the sample.) I's diameter < 20mm, Executing are crushed with a 13 KN	ition impact test. om a height of ition crush test N with the crush	cell 170 disa with test	ernal tempera does not exc °C and there assemb ly and in 6 hours of	iture of eed is no I no fire				
iod										
			Q152, 擠壓部	式驗機 C	1437/撞擊浿	川試機	Q231			
nendation	The C	Cells pass the test.								
w Data	Crush Test on 50% Charged Cells No. Max. Temp.(°C) Other event 1 22.14 O 2 21.36 O 3 22.54 O 4 21.74 O 5 21.39 O									
	Short Circuit Test (UN38.3-5) iod uipment nendation W Data Test Item Crush test/ Impact test	Short Circuit Test (UN38.3-5) iod Start: 1	Short Circuit Test (UN38.3-5) Short Circuit Test (UN38.3-5) Short Circuit Test (UN38.3-5) Short Circuit Test (UN38.3-5) Short Circuit Test on the packs are observed for a further or the cell temperature return the packs are observed for a further or the cell temperature return the packs are observed for a further or the cell temperature return the packs are observed for a further or the cell temperature return the packs are observed for a further or the cell temperature return the packs are observed for a further or the cell temperature return the packs are observed for a further or the cell temperature return the packs are observed for a further or the cell temperature return the packs are observed for a further or the cell temperature return the packs are observed for a further or the cell temperature return the packs are observed for a further or the cell set of the cell se	Short Circuit Test (UN38.3-5) Short Circuit Test on Charged Packs are observed for a further 6 hours. Short Circuit Test on Charged Packs are observed for a further 6 hours. Short Circuit Test on Charged Packs are observed for a further 6 hours. Short Circuit Test on Charged Packs are observed for a further 6 hours. Short Circuit Test on Charged Packs are observed for a further 6 hours. Short Circuit Test on Charged Packs are observed for a further 6 hours. Short Circuit Test on Charged Packs are observed for a further 6 hours. Short Circuit Test on Charged Packs are observed for a further 6 hours. Short Circuit Test on Charged Packs are observed for a further 6 hours. Short Circuit Test on Charged Packs are observed for a further 6 hours. Short Circuit Test on Charged Packs are observed for a further 6 hours. Short Circuit Test on Charged Packs are observed for a further 6 hours. Short Circuit Test on Charged Packs are observed for a further 6 hours. Short Circuit Test on Charged Packs are observed for a further 6 hours. Short Circuit Test on Charged Packs are observed for St. Are 0.0 Other ext. Short Circuit Test on Charged Packs are observed for St. Are 0.0 Other ext. Short Circuit Test on Charged Packs are observed for St. Are 0.0 Other ext. Short Circuit Test on Charged Packs are observed for a further 6 hours. Short Circuit Test on Charged Packs are observed for a further 6 hours. Short Circuit Test on Charged Packs are observed for a further 6 hours. Short Circuit Test on Charged Packs are observed for a further 6 hours. Short Circuit Test on Charged Packs are observed for a further 6 hours. Short Circuit Test on Charged Packs are observed for a further 6 hours. Short Circuit Test on Charged Packs are observed for a further 6 hours. Short Circuit Test on Charged Packs are observed for a further 6 hours. Short Circuit Test on	Short Circuit Test (UN38.3-5) Short Circuit Test of the packs are observed for a further 6 hours. Short Circuit Test on Charged Packs (Exterior packs are observed for a further 6 hours. Short Circuit Test on Charged Packs (Exterior packs are observed for a further 6 hours. Short Circuit Test on Charged Packs (Exterior packs are observed for a further 6 hours. Short Circuit Test on Charged Packs (Exterior packs are observed for a further 6 hours. Short Circuit Test on Charged Packs (Exterior packs are observed for a further 6 hours. Short Circuit Test on Charged Packs (Exterior packs are observed for a further 6 hours. Short Circuit Test on Charged Packs (Exterior packs are observed for a further 6 hours. Short Circuit Test on Charged Packs (Exterior packs are observed for a further 6 hours. Short Circuit Test on Charged Packs (Exterior packs are observed for a further 6 hours. Short Circuit Test on Charged Packs (Exterior packs are observed for a further 6 hours. Short Circuit Test on Charged Packs (Exterior packs are observed for a further 6 hours. Short Circuit Test on Charged Packs (Exterior packs are observed for a further 6 hours. Short Circuit Test on Charged Packs (Exterior packs are observed for Charged Cells (Exterior packs) (Exterior packs are observed for a further 6 hours. Short Circuit Test on Charged Cells (Exterior packs are packs are observed for a further 6 hours. Short Circuit Test on Charged Cells (Exterior packs are packs are packs are packs are packed for a further 6 hours. Circush test (Hours are packed for a further 6 hours. Circush test (Hours are packed for a further 6 hours. Circush test (Hours are packed for a further 6 hours. Circush test (Hours are packed for a further 6 hours. Circush test (Hours are packed for a further 6 hours. Circush test (Hours are packed for a further 6 hours. Circush test (Hours are	Short Circuit Test on Charged Packs No. Max Temp (°C) Other event 1 S4.26 O S2.55.68 O S3 56.81 O S4.23 O S5.47 O S5	5-1.Packs are placed in to a 55½°C oven, and exterior packs temperature are monitored 5-2.When packs exterior reach 55½°C, the year eshorted by connecting terminals with a copper wire of resistance less than 100m Ohm. 5-4. The short was continued for more than 1 hour or the cell temperature return to 55°C. The packs are observed for a further 6 hours. iod Start: 2016/03/10 End:2016/03/12 spipment \$\frac{\text{Short Circuit Test on Charged Packs}}{\text{No.}}\$ No. Max. Temp.(°C) Other event 1 5-1.Cells pass the test/ (The cells are crushed with a 13 KN with the crush test/. Once the force is obtained it is to be released.) Short Circuit Test on Charged Packs No. Max. Temp.(°C) Other event 1 5-1.Cells pass the test/ (The cells are crushed with a 13 KN with the crush test/. Crush test/ (The cells are crushed with a 13 KN with the crush tester. Once the force is obtained it is to be released.) W Data 5-1.Cells pass the test. Crush Test on Charged Packs No. Max. Temp.(°C) Other event 2 5-2.Cell's diameter < 20mm, Execution impact test. (Che 12.5cm onto the sample.) Impact test/ (The cells are crushed with a 13 KN with the crush tester. Once the force is obtained it is to be released.) The Cells pass the test. Crush Test on 50% Charged Cells No. Max. Temp.(°C) Other event 1 1 22.14 O Other event 1 2 2.138 O Other event 1 2 2.138 O Other event 1 2 2.144 O Other event 1 2 2.144 O Other event 1 2 2.174 O Other event 1 2 2.174 O Other event 1 3 2.2.64 O Other event 1 2 2.174 O Other event 1 2 2.174 O Other event 1 3 2.2.54 O Other event 1 4 pack darage 4 packs are monitored state. (Returnal temperature of cell does not exceed the state. (Packs of the packs of			



9/	corporation											
Item	Test Item		Test	specification		Judge criteria	Sample(s)					
Т7	Overcharge test (UN38.3-7)	7-2.The (a) W mc the ba (b) W tha tim 7-3. Tes	e charge current shaped commended maximude minimum voltage of them the Spec's recover than 18V, the mines there or 22V. Then the Spec's recover than 18V, the minimum than 18V, the minimum charts are to be conducted and the state of the test shaped commended that the state of the state of the test shaped commended that the state of the state	No disassembly, no fire within seven days after the test.	4 packs are fully charged (Pack#9~12) 4 packs are 50 times cycled ending in fully charged state (Pack #13~16)							
Test Per	iod		2016/03/07 End:2016/03/10									
Test Equ	ipment	數位電	宣表 Q153, 資料	₩集器 Q160,	電源供應器C	148/Q149/Q1	50					
Major Pi	oblem	-										
Warning	Point	-										
	nendation	The p	acks pass the	test.								
			Overcharge Test on Charged Packs Charge Charge No. 75 (20) Other 1997									
		No.	Charge Voltage(V)	Current(A)	Max. Tem	p.(℃) (Other event					
		9			21.36	3	0					
		10			21.57		0					
		11			22.14		0					
Ra	w Data	12	22.0 V	4.9	21.68 22.23		0					
		14			21.67		0					
		15			21.84		0					
		16			22.25	5	0					
		Note:	D-Disassembly	; F-Fire / O-No	Disassembly	No Fire						
				, 7 0 110		,						



- 07	Corporation							
Item	Test Item			Test specification		Jud	dge criteria	Sample(s)
Т8	Forced discharge test (UN38.3-8)	conne initial	hall be forced di ecting it in series current equal to fied by the manu	10 cells are first cycle in fully discharged states (Pack#6~15) 10 cells are after 50 cycles ending in fully discharged states (Pack #16~25)				
Test Per	iod	Start	:: 2016/03/03	End:2016/03	3/04			
Test Equ	ipment			資料收集器 Q160,		供應器 Q147	/Q236/Q23	37
Major Pr		-		X 11 be Will at 1003	-0.//11	77/10/10/10/10/10	, , , , , , , ,	-
		_						
Warning			nooko noos	the test				
Recomn	nendation	rne	packs pass	the test.				
		Ford	ed discharge are fi	irst cycle in fully discharged Other event	Forced	d discharge are aft		ding in fully discharged Other event
		6	42.56	Other event	16	63.47	/	O
		7	60.37	0	17	69.48		0
		8	72.45	0	18	70.24		0
		9	52.71	0	19	68.43		0
		10	58.69 62.48	0	20 21	49.15 58.43		0
		12	71.69	0	22	71.21		0
		13	48.16	0	23	61.25		0
		14	64.15	0	24	48.19		0
		15	54.81	0	25	57.26		0
Ra	w Data	Note:D	-Disassembly ; F-Fi	re / O-No Disassembly , No F	ire			